

PATENT APPLICATION

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 IN THE U.S. PATENT AND TRADEMARK OFFICE 10/552517

October 7, 2005

Applicant: Hiroshi SEKIYA

For : STAINING PREVENTION METHOD FOR DRY PART OF PAPER  
 MACHINE AND STAINING INHIBITOR USED FOR THE METHOD

PCT International Application No.: PCT/JP2004/004462

PCT International Filing Date: March 29, 2004

U.S. Application No.

(if known, see 37 CFR 1.5): Unknown

Atty. Docket No.: 4414.P0684US

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 Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Sir:

In compliance with the provisions of Rules 1.97(b)(1) and 1.98, enclosed herewith is a copy of the International Search Report, Form PTO-1449 and the references cited thereon. The relevance of these references is explained on the enclosed search report. Accordingly, further comment at this point in time should not be necessary.

Respectfully submitted,

  
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Encl: Copy of International Search Report  
 Form PTO-1449 and one copy of each reference listed  
 thereon

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INFORMATION  
DISCLOSURE  
CITATION

Applicant: Hiroshi SEKIYA

Ser.No.: Unknown

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Group: Unknown

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## U.S. PATENT DOCUMENTS

Examiner Initials*	Cite No.	Document Number - Kind Code	Publication Date MM-DD-YYYY	Name of Patentee or Applicant
	AA	6 468 394	10-22-2002	SEKIYA et al
	AB			
	AC			
	AD			
	AE			
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	AG			
	AH			
	AI			
	AJ			
	AK			

## FOREIGN PATENT DOCUMENTS

Examiner Initials*	Cite No.	Country Code - Document Number - Kind Code	Publication Date MM-DD-YYYY	Name of Patentee or Applicant	Trans.
	AL	EP 1 124 006 A1	08-16-2001	SEKIYA	
	AM	JP 62-215098	09-21-1987		No
	AN	JP 7-279081	10-24-1995		No
	AO	JP 2000-96478	04-04-2000		No
	AP	JP 2000-345489	12-12-2000		No

## NON PATENT LITERATURE DOCUMENTS

Examiner Initials*	Cite No.	(Include Author, Title, Date, Pages, Etc.)
	AQ	
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EXAMINER SIGNATURE		DATE CONSIDERED

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.